

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	1	10/718640	US-PGPUB; USPAT; USOCR	OR	ON	2006/06/25 19:40
S2	1988	445/24.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2006/06/25 16:28
S3	1	("2004/0104197").URPN.	USPAT	OR	ON	2006/06/25 16:28
S4	393	"445"/\$ and "216"/\$	US-PGPUB; USPAT; USOCR	OR	ON	2006/06/25 19:41
S5	1	"5707745".pn.	US-PGPUB; USPAT; USOCR	OR	ON	2006/06/25 17:35
S6	16	("20030101932" "20030221613" "20040104197" "20040115342" "20040123799" "4167413" "4511599" "4615781" "4715940" "4780382" "5260151" "5567267" "6177218" "6475287" "6749690" "6858086").PN. OR ("6955726").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/06/25 18:11
S7	781	216/20.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2006/06/25 19:40
S8	1	"445"/\$ and "216"/\$ and (evaporation near1 mask)	US-PGPUB; USPAT; USOCR	OR	ON	2006/06/25 19:43
S9	146	(evaporation near1 mask) same mask same (aperture hole)	US-PGPUB; USPAT; USOCR	OR	ON	2006/06/25 20:18
S10	5	"20030101932" "20020025406" "20010019807" ("5652067" "6858086").pn.	US-PGPUB; USPAT; USOCR	OR	ON	2006/06/25 20:16
S11	359	(deposition near1 mask) same mask same (aperture hole)	US-PGPUB; USPAT; USOCR	OR	ON	2006/06/25 20:42
S12	131	((evaporation deposition) near1 mask) same mask same (aperture hole)	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/25 20:46
S13	4	((evaporation deposition) near1 mask) same (dummy near2 (aperture hole))	US-PGPUB; USPAT; USOCR	OR	ON	2006/06/25 20:43
S14	3	"2002060927"	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/25 20:46

EAST Search History

S15	1	2002-410090.NRAN.	DERWENT	OR	ON	2006/06/25 20:46
S16	3	"2002252083"	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/25 20:47
S17	3	"2002012238"	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/25 20:47
S18	11	(method manufacture manufacturing) same (OELD OLED (organic near1 electroluminescent)) same ((evaporation deposition) near1 mask) same electrode	US-PGPUB; USPAT; USOCR	OR	ON	2006/06/25 21:19